

## 1. General description

AC Thyristor power switch in a SOT223-2L surface-mountable plastic package with self-protective capabilities against low and high energy transients.

## 2. Features and benefits

- Common terminal on mounting base allows multiple ACTs on shared cooling pad
- Exclusive negative gate triggering
- Full cycle AC conduction
- High voltage capability
- Remote gate separates the gate driver from the effects of the load current
- Safe clamping of low energy over-voltage transients
- Self-protective turn-on during high energy voltage transients
- Surface-mountable package
- Very high noise immunity

## 3. Applications

- Fan motor circuits
- Pump motor circuits
- Lower-power highly inductive, resistive and safety loads
- Contactors, circuit breakers, valves, dispensers and door locks

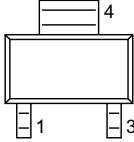
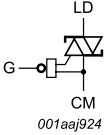
## 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes	Values			Unit
<b>Absolute maximum rating</b>							
$V_{DRM}$	repetitive peak off-state voltage			800			V
$I_{T(RMS)}$	RMS on-state current	full sine wave; $T_{sp} \leq 76\text{ °C}$ ; <a href="#">Fig. 1</a> ; <a href="#">Fig. 2</a> ; <a href="#">Fig. 3</a>		1.5			A
$I_{TSM}$	non-repetitive peak on-state current	full sine wave; $T_{j(init)} = 25\text{ °C}$ ; $t_p = 20\text{ ms}$ ; <a href="#">Fig. 4</a> ; <a href="#">Fig. 5</a>		16			A
		full sine wave; $T_{j(init)} = 25\text{ °C}$ ; $t_p = 16.7\text{ ms}$		17.6			A
$T_j$	operating junction temperature			-40 to 125			°C
$V_{PP}$	peak pulse voltage	$T_j = 25\text{ °C}$ ; non-repetitive, off-state; <a href="#">Fig. 6</a>		2.5			kV
Symbol	Parameter	Conditions	Notes	Min	Typ	Max	Unit
<b>Static characteristics</b>							
$I_{GT}$	gate trigger current	$V_D = 12\text{ V}$ ; $I_T = 0.1\text{ A}$ ; LD+ G-; $T_j = 25\text{ °C}$ ; <a href="#">Fig. 8</a>		-	-	10	mA
		$V_D = 12\text{ V}$ ; $I_T = 0.1\text{ A}$ ; LD- G-; $T_j = 25\text{ °C}$ ; <a href="#">Fig. 8</a>		-	-	10	mA
$I_H$	holding current	$V_D = 12\text{ V}$ ; $T_j = 25\text{ °C}$ ; <a href="#">Fig. 10</a>		-	-	20	mA
$V_T$	on-state voltage	$I_T = 1.1\text{ A}$ ; $T_j = 25\text{ °C}$ ; <a href="#">Fig. 11</a>		-	-	1.35	V
$V_{CL}$	clamping voltage	$I_{CL} = 0.1\text{ mA}$ ; $t_p = 1\text{ ms}$		850	-	-	V

## 5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	LD	load		
3	G	gate		
4	CM	common		

## 6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
ACT110V-800E	SOT223-2L	ACT110V-800EF	Reel	4000	SOT223d-2L	02-Apr-2025

## 7. Marking

Table 4. Marking codes

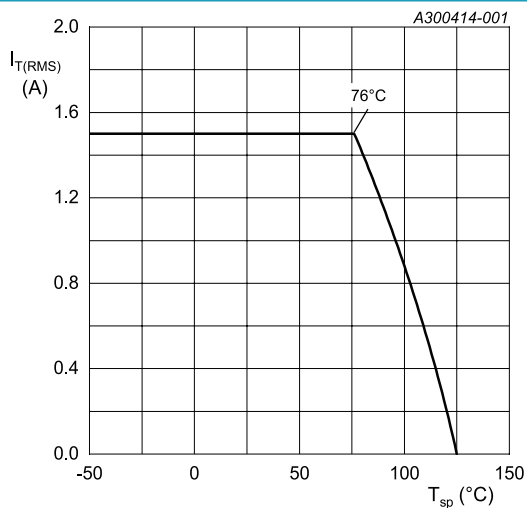
Type number	Marking codes
ACT110V-800E	110V8E

## 8. Limiting values

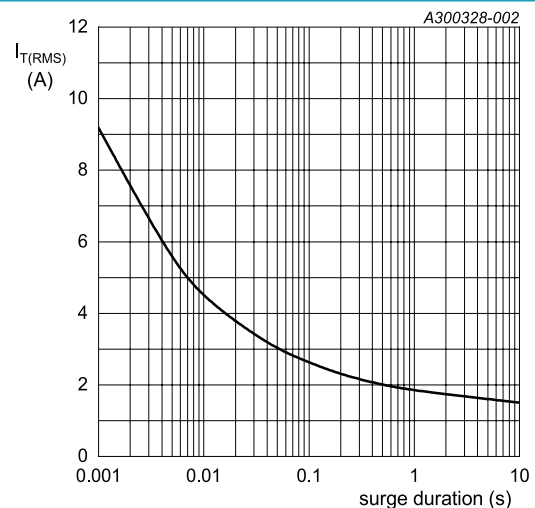
**Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage			800	V
$V_{RRM}$	repetitive peak reverse voltage			800	V
$I_{T(RMS)}$	RMS on-state current	full sine wave; $T_{sp} \leq 76\text{ °C}$ ; <a href="#">Fig 1</a> ; <a href="#">Fig 2</a> ; <a href="#">Fig 3</a>		1.5	A
$I_{TSM}$	non-repetitive peak on-state current	full sine wave; $T_{j(imit)} = 25\text{ °C}$ ; $t_p = 20\text{ ms}$ ; <a href="#">Fig 4</a> ; <a href="#">Fig 5</a>		16	A
		full sine wave; $T_{j(imit)} = 25\text{ °C}$ ; $t_p = 16.7\text{ ms}$		17.6	A
$I^2t$	$I^2t$ for fusing	$t_p = 10\text{ ms}$ ; SIN		1.28	A <sup>2</sup> s
$di_T/dt$	rate of rise of on-state current	$I_G = 20\text{ mA}$		100	A/ $\mu$ s
$I_{GM}$	peak gate current	$t = 20\text{ }\mu$ s		1	A
$V_{GM}$	peak gate voltage	$t = 20\text{ }\mu$ s		15	V
$P_{GM}$	peak gate power			0.1	W
$T_{stg}$	storage temperature			-40 to 150	°C
$T_j$	operating junction temperature			-40 to 125	°C
$V_{PP}$	peak pulse voltage	$T_j = 25\text{ °C}$ ; non-repetitive, off-state; <a href="#">Fig. 6</a>		2.5	kV



**Fig. 1. RMS on-state current as a function of solder point temperature; maximum values**



$f = 50\text{ Hz}$ ;  $T_{sp} = 76\text{ °C}$   
**Fig. 2. RMS on-state current as a function of surge duration; maximum values**

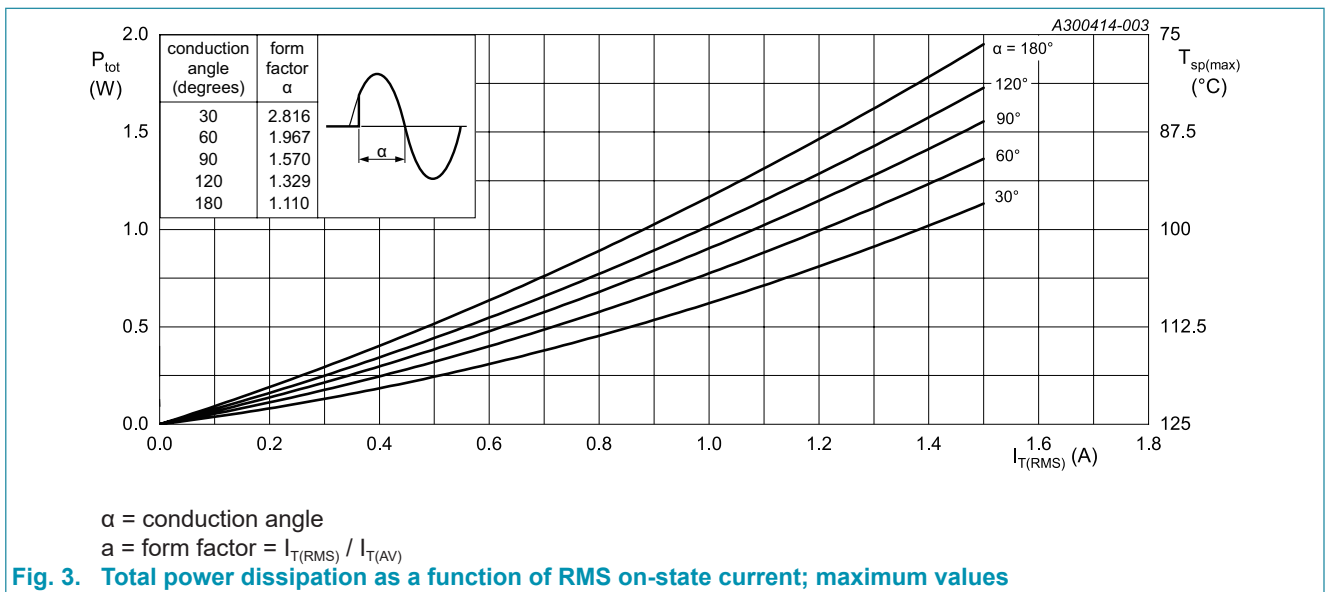


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

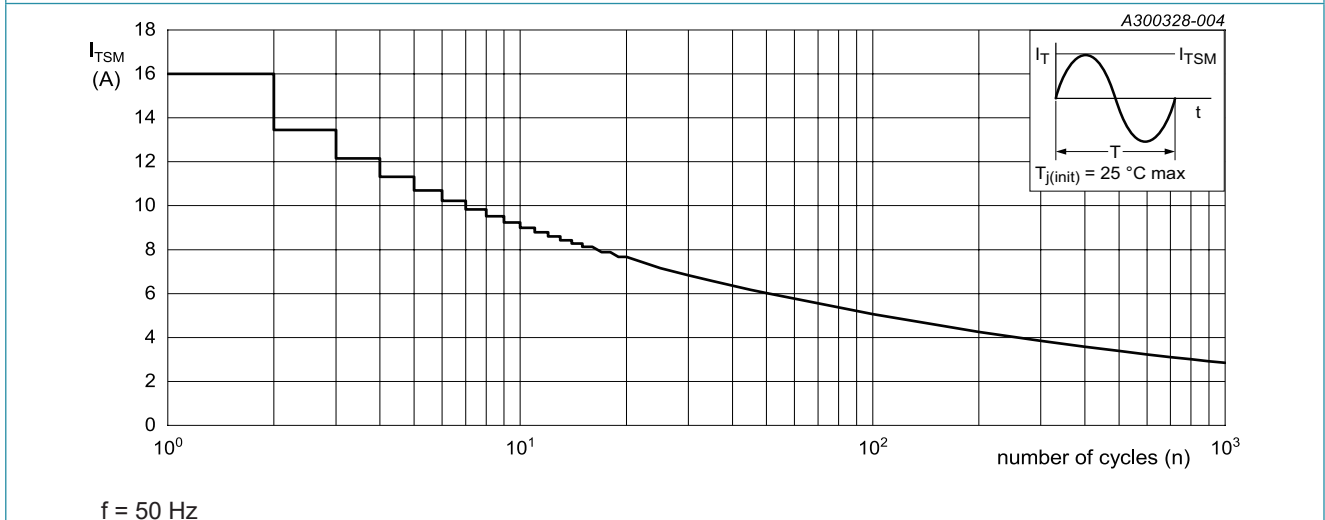


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

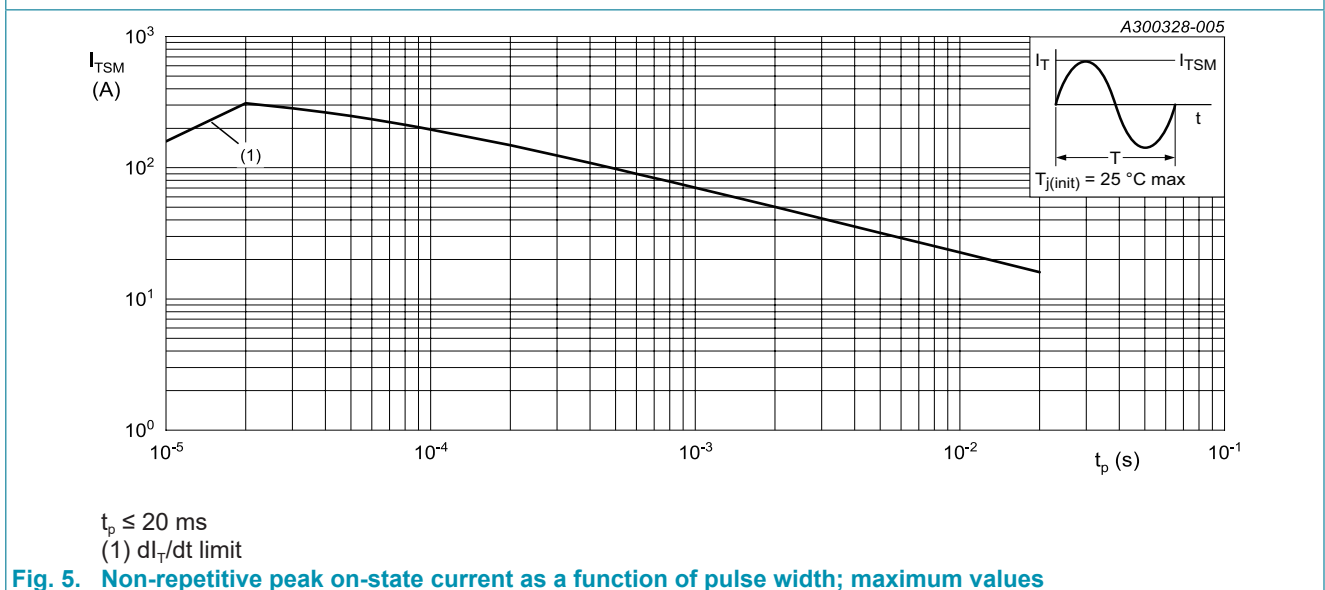


Fig. 5. Non-repetitive peak on-state current as a function of pulse width; maximum values

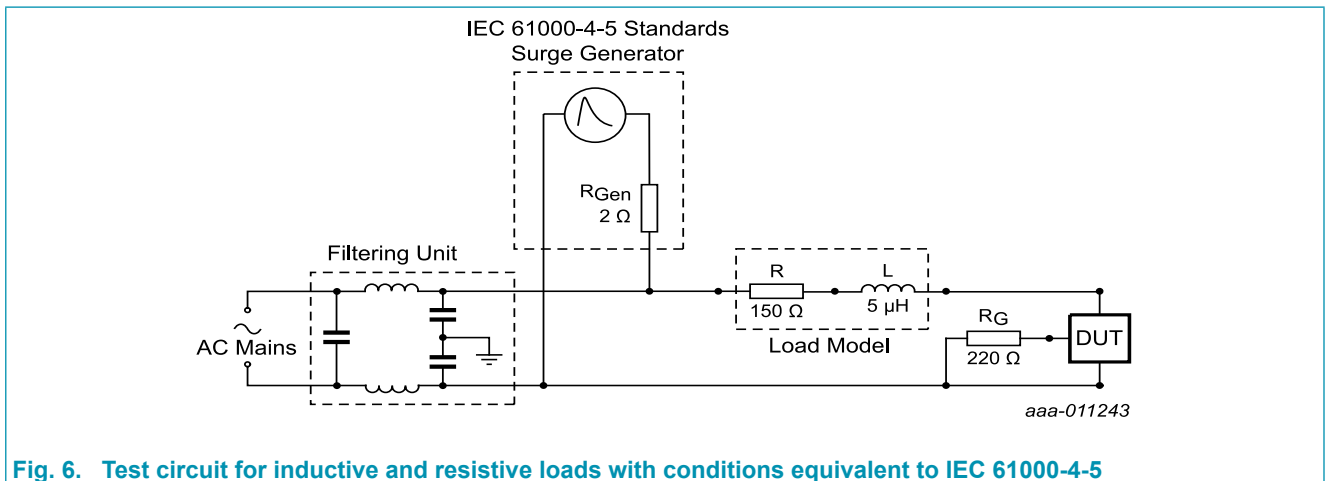


Fig. 6. Test circuit for inductive and resistive loads with conditions equivalent to IEC 61000-4-5

## 9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Notes	Min	Typ	Max	Unit
$R_{th(j-sp)}$	thermal resistance from junction to solder point	full cycle; Fig 7		-	-	25	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air; printed-circuit board mounted; pad area		-	65	-	K/W

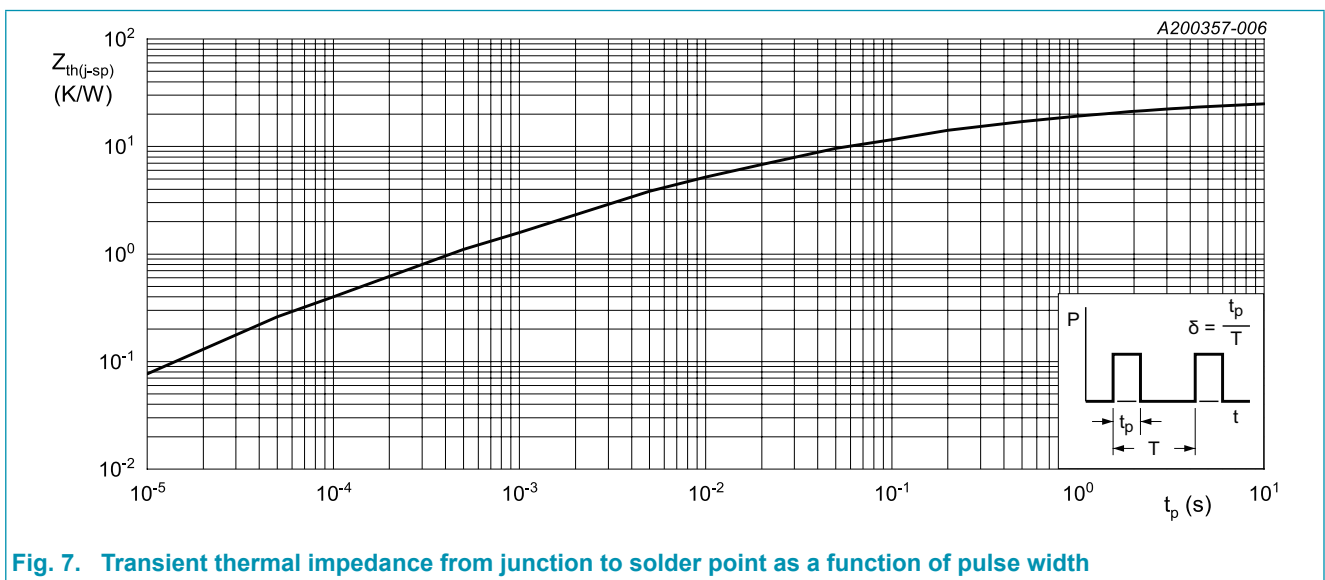
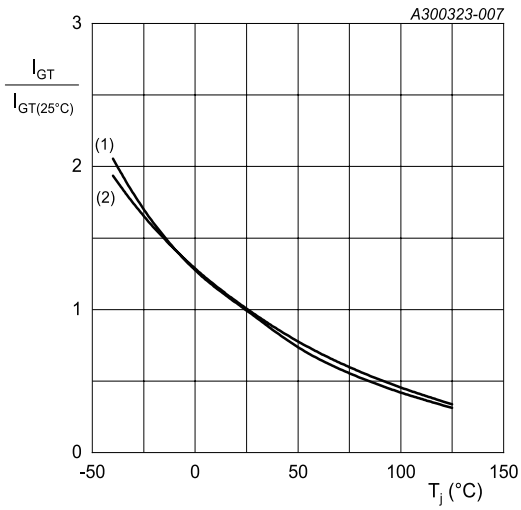


Fig. 7. Transient thermal impedance from junction to solder point as a function of pulse width

## 10. Characteristics

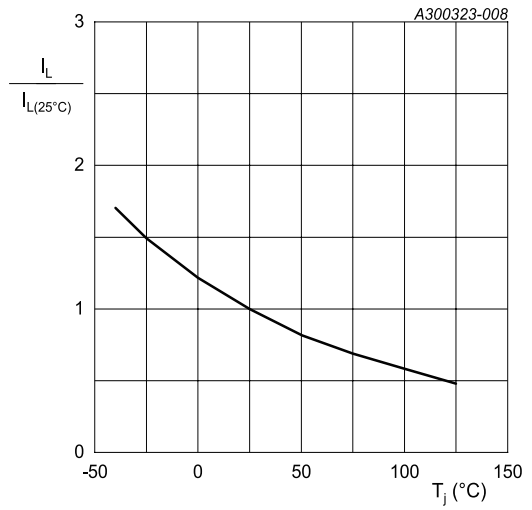
Table 7. Characteristics

Symbol	Parameter	Conditions	Notes	Min	Typ	Max	Unit
<b>Static characteristics</b>							
$I_{GT}$	gate trigger current	$V_D = 12\text{ V}$ ; $I_T = 0.1\text{ A}$ ; LD+ G-; $T_J = 25\text{ °C}$ ; <a href="#">Fig. 8</a>		-	-	10	mA
		$V_D = 12\text{ V}$ ; $I_T = 0.1\text{ A}$ ; LD- G-; $T_J = 25\text{ °C}$ ; <a href="#">Fig. 8</a>		-	-	10	mA
$I_L$	latching current	$V_D = 12\text{ V}$ ; $I_G = 0.1\text{ A}$ ; LD+ G-; $T_J = 25\text{ °C}$ ; <a href="#">Fig. 9</a>		-	-	25	mA
		$V_D = 12\text{ V}$ ; $I_G = 0.1\text{ A}$ ; LD- G-; $T_J = 25\text{ °C}$ ; <a href="#">Fig. 9</a>		-	-	20	mA
$I_H$	holding current	$V_D = 12\text{ V}$ ; $T_J = 25\text{ °C}$ ; <a href="#">Fig. 10</a>		-	-	20	mA
$V_T$	on-state voltage	$I_T = 1.1\text{ A}$ ; $T_J = 25\text{ °C}$ ; <a href="#">Fig. 11</a>		-	-	1.35	V
$V_{GT}$	gate trigger voltage	$V_D = 12\text{ V}$ ; $I_T = 0.1\text{ A}$ ; $T_J = 25\text{ °C}$ ; <a href="#">Fig. 12</a>		-	-	1	V
		$V_D = 400\text{ V}$ ; $I_T = 0.1\text{ A}$ ; $T_J = 125\text{ °C}$		0.15	-	-	V
$I_D$	off-state current	$V_D = 800\text{ V}$ ; $T_J = 25\text{ °C}$		-	-	10	$\mu\text{A}$
		$V_D = 800\text{ V}$ ; $T_J = 125\text{ °C}$		-	-	2	mA
$I_R$	reverse current	$V_R = 800\text{ V}$ ; $T_J = 25\text{ °C}$		-	-	10	$\mu\text{A}$
		$V_R = 800\text{ V}$ ; $T_J = 125\text{ °C}$		-	-	2	mA
$V_{CL}$	clamping voltage	$I_{CL} = 0.1\text{ mA}$ ; $t_p = 1\text{ ms}$		850	-	-	V
<b>Dynamic characteristics</b>							
$dV_D/dt$	rate of rise of off-state voltage	$V_{DM} = 536\text{ V}$ ; $T_J = 125\text{ °C}$ ; ( $V_{DM} = 67\%$ of $V_{DRM}$ ); exponential waveform; gate open circuit		2000	-	-	$\text{V}/\mu\text{s}$
$dI_{com}/dt$	rate of change of commutating current	$V_D = 400\text{ V}$ ; $T_J = 125\text{ °C}$ ; $I_{T(RMS)} = 1.5\text{ A}$ ; $dV_{com}/dt = 20\text{ V}/\mu\text{s}$ ; (snubberless condition); gate open circuit		0.5	-	-	$\text{A}/\text{ms}$

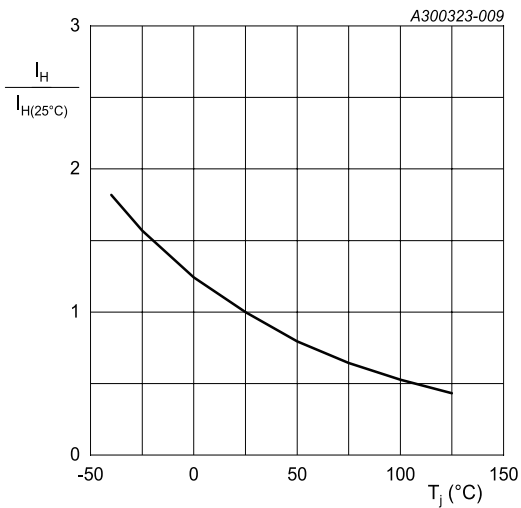


(1) LD+ G-  
(2) LD- G-

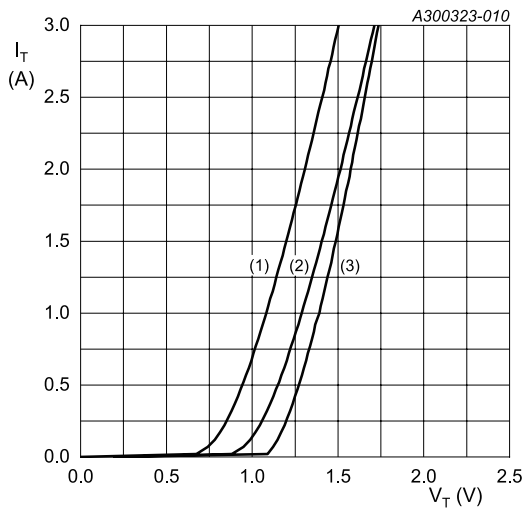
**Fig. 8. Normalized gate trigger current as a function of junction temperature**



**Fig. 9. Normalized latching current as a function of junction temperature**

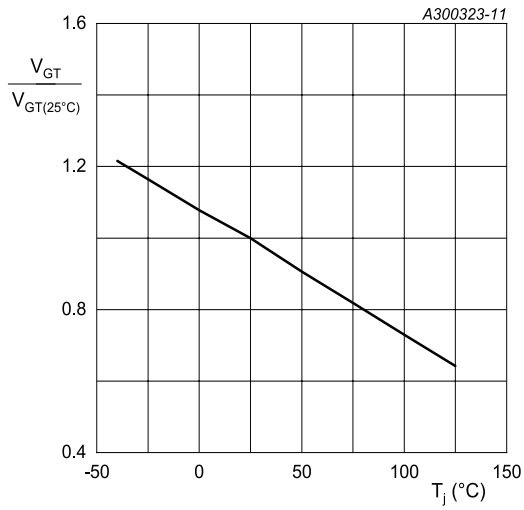


**Fig. 10. Normalized holding current as a function of junction temperature**

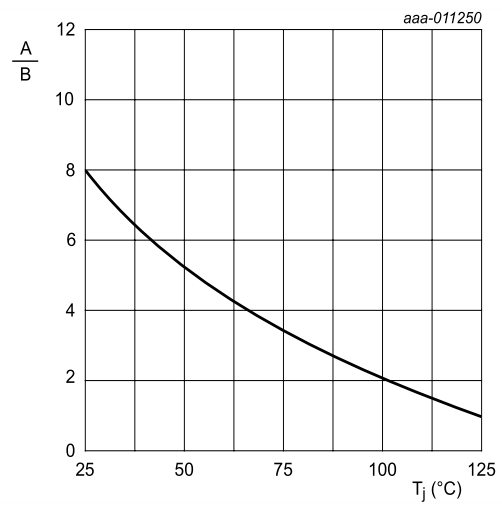


$V_o = 0.999 \text{ V}; R_s = 0.2667 \Omega$   
(1)  $T_j = 125 \text{ }^\circ\text{C}$ ; typical values  
(2)  $T_j = 125 \text{ }^\circ\text{C}$ ; maximum values  
(3)  $T_j = 25 \text{ }^\circ\text{C}$ ; maximum values

**Fig. 11. On-state current as a function of on-state voltage**

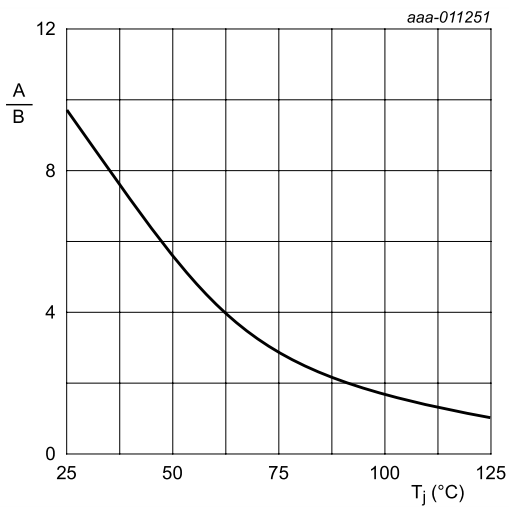


**Fig. 12. Normalized gate trigger voltage as a function of junction temperature**



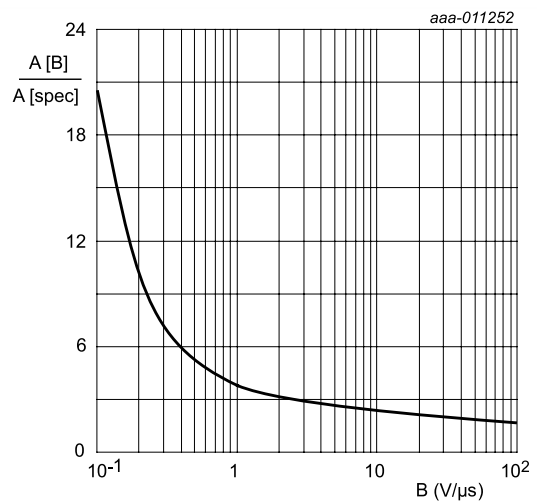
A =  $dV_D/dt$  at condition  $T_j$  °C  
B =  $dV_D/dt$  at condition  $T_j$  [125] °C

**Fig. 13. Normalized rate of rise of off-state voltage as a function of junction temperature**



A =  $dI_{com}/dt$  at condition  $T_j$  °C  
B =  $dI_{com}/dt$  at condition  $T_j$  [125] °C  
 $V_D = 400$  V

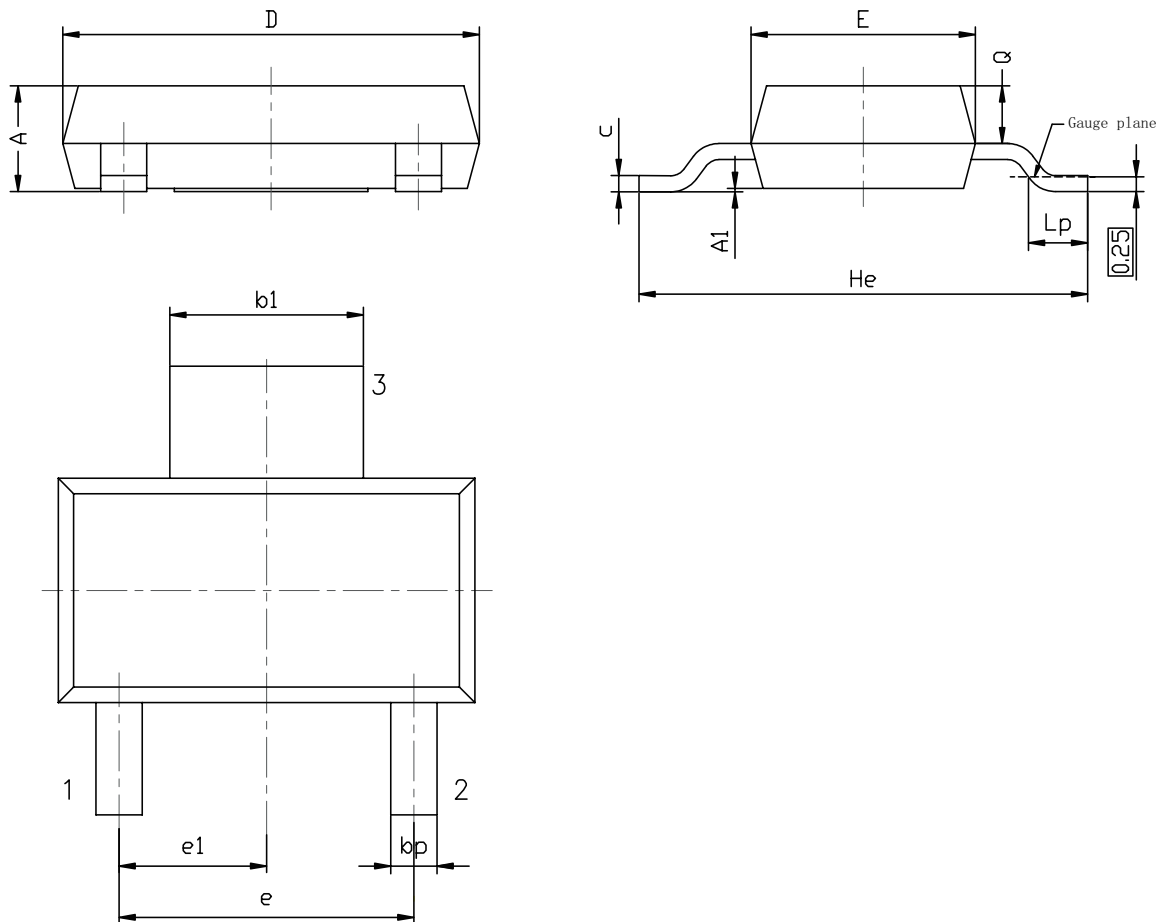
**Fig. 14. Normalized critical rate of rise of commutating current as a function of junction temperature**



A [B] =  $dI_{com}/dt$  at condition B,  $dV_{com}/dt$   
A [spec] is the data sheet value for  $dI_{com}/dt$   
turn-off time is less than 20 ms

**Fig. 15. Normalized critical rate of change of commutating current as a function of critical rate of change of commutating voltage; minimum values**

### 11. Package outline



Unit	A	A1	bp	b1	c	D	E	e	e1	He	Lp	Q	
mm	Min	1.50	0.01	0.66	2.90	0.23	6.30	3.30	4.50	2.20	6.70	0.75	0.82
	Max	1.81	0.12	0.85	3.13	0.35	6.70	3.70	4.70	2.40	7.30	1.20	0.93

## 12. Legal information

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Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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